

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application		OFC No. P/1805-17			
		Applicant Markus TURTINEN et al					
		Filing Date		Group Art Unit			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
	US-						
	US-						
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<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	10318937 A	12-1998	Japan			Abstract	
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
		International Search Report for PCT/FI03/00626 dated November 7, 2003					
		"An Adaptive Texture and Shape Based Defect Classification" by Jukka Iivarinen et al., 1998.					
		"Content-Based Image Retrieval in Surface Inspection" by Jukka Iivarinen et al., 2002.					
		"HIERARCHICAL Neural Network for COLOR Classification" by A. Verikas et al., 1994.					
Examiner		Date Considered					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							